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Morteza Safai
Jeff R. Brown
Editors

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Contents

vii *Conference Committee*

SESSION 1 PYROMETRY AND RADIOMETRY

- 8013 02 **A polynomial regression approach to subpixel temperature extraction from a single-band thermal infrared image** [8013-01]
S. E. Paul, C. Salvaggio, Rochester Institute of Technology (United States)
- 8013 05 **Thermoreflectometry: a new system to determine the true temperature fields on surface with unknown emissivities** [8013-04]
R. Gilblas, T. Sentenac, Toulouse Univ. (France); D. Hernandez, Procedes, Materiaux et Energie Solaire, CNRS, National Ctr. of Scientific Research (France); Y. Le Maoult, Toulouse Univ. (France)

SESSION 2 INDUSTRIAL APPLICATIONS: BIOLOGICAL

- 8013 06 **Use of infrared imaging for investigation of chicken embryo development** [8013-05]
R. A. Frye, Vanderbilt Univ. (United States); S.-J. Hsieh, J. B. D. Girón Palomares, Texas A&M Univ. (United States)
- 8013 07 **Dynamic infrared imaging for biological and medical applications in Boron neutron capture therapy** [8013-06]
G. A. Santa Cruz, National Atomic Energy Commission (Argentina); S. J. González, National Atomic Energy Commission (Argentina) and National Research Council (Argentina); A. Dagrosa, A. E. Schwint, National Research Council (Argentina) and National Atomic Energy Commission (Argentina); M. Carpano, National Atomic Energy Commission (Argentina); V. A. Trivillin, National Research Council (Argentina) and National Atomic Energy Commission (Argentina); E. F. Boggio, National Atomic Energy Commission (Argentina); J. Bertotti, Favaloro Univ. (Argentina); J. Marín, A. Monti Hughes, A. J. Molinari, National Atomic Energy Commission (Argentina); M. Alberio, INVAP SE (Argentina)

SESSION 3 INDUSTRIAL APPLICATIONS: BUILDINGS

- 8013 08 **Using a combination of aerial infrared and handheld infrared cameras for measuring, analyzing, and prioritizing the thermal performance of "big box" buildings** [8013-07]
G. R. Stockton, Stockton Infrared Thermographic Services, Inc. (United States); R. G. Lucas, RecoverIR Inc. (United States)
- 8013 09 **Improvement of energy efficiency: the use of thermography and air-tightness test in verification of thermal performance of school buildings** [8013-08]
T. Kauppinen, S. Siikanen, VTT Technical Research Ctr. of Finland (Finland)

- 8013 0A **A hybrid, infrared thermography: heat diffusion equation, method for the 3D air-temperature measurement** [8013-09]
F. B. Djupkep Dizeu, X. Maldague, A. Bendada, Univ. Laval (Canada); E. Grinzato, P. Bison, CNR, ITC (Italy)

SESSION 4 INDUSTRIAL APPLICATIONS: PETROCHEMICAL AND PIPELINE APPLICATIONS

- 8013 0B **IR gas cloud imaging in oil and gas applications: immunity to false stimuli** [8013-10]
E. Naranjo, S. Baliga, J. Park, General Monitors (United States); P. Bernascolle, Bertin Technologies (France)
- 8013 0C **Development of a gas leak detection method based on infrared spectrum imaging utilizing microbolometer camera** [8013-11]
T. Sakagami, Kobe Univ. (Japan); H. Anzai, S. Kubo, Osaka Univ. (Japan)
- 8013 0D **Detectivity of gas leakage based on electromagnetic radiation transfer** [8013-12]
Y. Long, L. Wang, J. Li, C. Zhang, B. Zhang, Beijing Institute of Technology (China)
- 8013 0F **Corrosion detection on pipelines by IR thermography** [8013-14]
P. Bison, S. Marinetti, G. Cuogo, CNR, ITC (Italy); B. Molinas, P. Zonta, Venezia Tecnologie S.p.A (Italy); E. Grinzato, CNR, ITC (Italy)

SESSION 5 INDUSTRIAL APPLICATIONS: ELECTRONICS

- 8013 0H **Comparative analysis of pulse and active thermography for investigating solder joint geometry prediction** [8013-16]
B. M. Vela, S.-J. Hsieh, J. B. D. Girón Palomares, Texas A&M Univ. (United States)
- 8013 0I **Using 3D infrared imaging to calibrate and refine computational fluid dynamic modeling for large computer and data centers** [8013-17]
G. R. Stockton, United Infrared, Inc. (United States)
- 8013 0J **Infrared imaging of LED lighting tubes and fluorescent tubes** [8013-18]
S. Siikanen, S. Kivi, T. Kauppinen, M. Juuti, VTT Technical Research Ctr. of Finland (Finland)

SESSION 6 INDUSTRIAL APPLICATIONS: SOLAR CELLS

- 8013 0K **A thermographic survey for evaluating in situ the performance of photovoltaic panels** [8013-19]
N. P. Avdelidis, National Technical Univ. of Athens (Greece); Y. P. Markopoulos, I. A. Katsis, Green Project S.A. (Greece); M. Kouli, National Technical Univ. of Athens (Greece)
- 8013 0L **Infrared lock-in techniques for solar cell inspection** [8013-20]
R. A. Rotolante, MoviTherm (United States); B. Schneider, FLIR Systems, Inc. (United States)

SESSION 7 INDUSTRIAL APPLICATIONS: MISCELLANEOUS

- 8013 0P **High-speed IR monitoring of a turbojet engine gas flow using an uncooled MWIR imaging sensor** [8013-24]
R. Linares-Herrero, New Infrared Technologies, Ltd. (Spain); V. Archilla-Prat, Instituto Nacional de Técnica Aeroespacial (Spain); M. T. Montojo-Superviellea, R. Gutiérrez-Álvarez, G. Vergara, A. Baldasano-Ramírez, New Infrared Technologies, Ltd. (Spain); D. Mercader, A. Jiménez, Instituto Nacional de Técnica Aeroespacial (Spain)
- 8013 0Q **Implementation of thermographers' certification in Brazil** [8013-26]
L. dos Santos, Furnas Centrais Elétricas S.A. (Brazil); L. M. Alves, ABENDI (Brazil); E. da Costa Bortoni, Univ. Federal de Itajubá (Brazil)

SESSION 8 IR NDT THEORY I

- 8013 0R **Signal and image processing techniques for digitized frequency modulated thermal-wave imaging for characterization of fiber-reinforced plastics** [8013-27]
R. Mulaveesala, S. V. Ghali, L. K. Balyan, S. S. Lamba, Indian Institute of Information Technology (India)
- 8013 0S **Automatic thermographic image defect detection of composites** [8013-28]
B. Luo, B. Liebenberg, J. Raymont, S. Santospirito, Kingston Computer Consultancy Ltd. (United Kingdom)
- 8013 0T **Fixed eigenvector analysis of thermographic NDE data** [8013-29]
K. E. Cramer, W. P. Winfree, NASA Langley Research Ctr. (United States)

SESSION 9 IR NDT THEORY II

- 8013 0U **Improved flaw detection and characterization with difference thermography** [8013-30]
W. P. Winfree, J. N. Zalameda, P. A. Howell, NASA Langley Research Ctr. (United States)
- 8013 0V **Defense and illustration of time-resolved pulsed thermography for NDE (Invited Paper)** [8013-31]
D. L. Balageas, ONERA (France)

SESSION 10 IR NDT METHODS AND APPLICATIONS

- 8013 0W **Automated transient thermography for the inspection of CFRP structures: experimental results and developed procedures** [8013-32]
P. Theodorakeas, National Technical Univ. of Athens (Greece); N. P. Avdelidis, National Technical Univ. of Athens (Greece) and Univ. Laval (Canada); K. Hrissagis, National Technical Univ. of Athens (Greece); C. Ibarra-Castanedo, Univ. Laval (Canada); M. Kou, National Technical Univ. of Athens (Greece); X. Maldague, Univ. Laval (Canada)
- 8013 0Y **Thinning identification technique using stainless steel film heater and response surface method** [8013-34]
N. Ogasawara, H. Yamada, National Defense Academy (Japan)

- 8013 10 **Detection of subsurface defects in aluminium with thermo-inductive inspection** [8013-36]
B. Oswald-Tranta, M. Sorger, Montan Univ. Leoben (Austria)
- 8013 12 **Pulse and lock-in IR NDT in complex structures** [8013-38]
M. Tarin, MoviTHERM (United States)
- 8013 13 **Infrared thermography as a nondestructive tool for materials characterisation and assessment** [8013-39]
N. P. Avdelidis, InnotecUK Ltd. (United Kingdom) and Univ. Laval (Canada); T.-H. Gan, TWI Ltd. (United Kingdom); C. Ibarra-Castaneda, X. P. V. Maldague, Univ. Laval (Canada)

SESSION 11 MATERIALS EVALUATION AND DETECTION

- 8013 14 **Fiber optic thermal detection of composite delaminations** [8013-40]
M.-C. Wu, W. P. Winfree, NASA Langley Research Ctr. (United States)
- 8013 15 **Thermoelastic stress analysis of overlap shear splices constructed from wet lay-up FRP composites** [8013-41]
J. Brown, B. Fineout, Hope College (United States)
- 8013 16 **Preliminary investigation of polarization effects during metal cutting** [8013-42]
E. P. Whitenton, National Institute of Standards and Technology (United States)
- 8013 18 **Modeling of laser-analyte-substrate interaction in photo-thermal infrared imaging and laser trace vaporization** [8013-44]
R. Furstenberg, J. Großer, C. A. Kendziora, M. R. Papantonakis, V. Nguyen, R. A. McGill, U.S. Naval Research Lab. (United States)
- 8013 19 **Application of micro-scale thermography to the thermal analysis of polymeric and organic materials** [8013-45]
J. Morikawa, Tokyo Institute of Technology (Japan); E. Hayakawa, ai-Phase Co., Ltd. (Japan); T. Hashimoto, Tokyo Institute of Technology (Japan)

Author Index

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(United States)

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1 Pyrometry and Radiometry

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Herbert Kaplan, Honeyhill Technical Company (United States)

- 2 Industrial Applications: Biological
Timo T. Kauppinen, VTT Technical Research Center of Finland (Finland)
Ralph B. Dinwiddie, Oak Ridge National Laboratory (United States)
Andrés E. Rozlosnik, SI Termografía Infrarroja (Argentina)
- 3 Industrial Applications: Buildings
Timo T. Kauppinen, VTT Technical Research Center of Finland (Finland)
Ralph B. Dinwiddie, Oak Ridge National Laboratory (United States)
Andrés E. Rozlosnik, SI Termografía Infrarroja (Argentina)
- 4 Industrial Applications: Petrochemical and Pipeline Applications
Timo T. Kauppinen, VTT Technical Research Center of Finland (Finland)
Ralph B. Dinwiddie, Oak Ridge National Laboratory (United States)
Andrés E. Rozlosnik, SI Termografía Infrarroja (Argentina)
- 5 Industrial Applications: Electronics
Timo T. Kauppinen, VTT Technical Research Center of Finland (Finland)
Ralph B. Dinwiddie, Oak Ridge National Laboratory (United States)
Andrés E. Rozlosnik, SI Termografía Infrarroja (Argentina)
- 6 Industrial Applications: Solar Cells
Nicolas P. Avdelidis, National Technical University of Athens (Greece)
Ralph A. Rotolante, MoviTherm (United States)
- 7 Industrial Applications: Miscellaneous
Nicolas P. Avdelidis, National Technical University of Athens (Greece)
Ralph A. Rotolante, MoviTherm (United States)
- 8 IR NDT Theory I
Douglas Burleigh, La Jolla Cove Consulting (United States)
Jeff R. Brown, Hope College (United States)
K. Elliott Cramer, NASA Langley Research Center (United States)
- 9 IR NDT Theory II
Douglas Burleigh, La Jolla Cove Consulting (United States)
Jeff R. Brown, Hope College (United States)
K. Elliott Cramer, NASA Langley Research Center (United States)
- 10 IR NDT Methods and Applications
Douglas Burleigh, La Jolla Cove Consulting (United States)
Jeff R. Brown, Hope College (United States)
K. Elliott Cramer, NASA Langley Research Center (United States)
- 11 Materials Evaluation and Detection
Takahide Sakagami, Kobe University (Japan)
Morteza Safai, The Boeing Company (United States)